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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF PATENT AND TRADEN	OOMMERCE MARK OFFICE MADEN	ATRY DOCKET NO. 208387US2			SERIAL NO. 09/855,665		
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15	AW	Whoi-Yul KIM, et al., IEEE, pages 391-396, "A PRACTICAL PATTERN RECOGNITION SYSTEM FOR TRANSLATION, SCALE AND ROTATION INVARIANCE", 1994							
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15	AY	P. SANGASSAPAVIRIYA, et al., IEEE TENCON-Speech and Image Technologies for Computing and Telecommunications, pages 203-206, "SIMILARITY MEASURES FOR COMPRESSED IMAGE DATABASES", 1997							
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Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through the Conformance and not considered. Include copy of this form with next communication to applicant.								<b>把®EIVED</b>	

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Form PTO 1449 (Modified)				ATTY DOCKET NO. 208387US2			SERIAL NO. 09/855,665		
LIST OF	LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideaki YAMAGATA, et al.				
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15	AE	5,987,162	11/16/99	Masafumi NAKATA	382	152			
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